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	Application No.	Applicant(s)
Notice of Allowability	10/813,503	LI ET AL.
	Examiner	Art Unit
	Pascal M. Bui-Pho	2878
	rascarw. Dul-riio	2070
The MAILING DATE of this communication appeal all claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R	(OR REMAINS) CLOSED in this applied or other appropriate communication IGHTS. This application is subject to	plication. If not included will be mailed in due course. THIS
1. \boxtimes This communication is responsive to <u>21 December 2005</u> .		
2. ⊠ The allowed claim(s) is/are <u>1-29</u> .		
 3. ☐ Acknowledgment is made of a claim for foreign priority ur a) ☐ All b) ☐ Some* c) ☐ None of the: 1. ☐ Certified copies of the priority documents have 		
2. Certified copies of the priority documents have been received in Application No		
3. Copies of the certified copies of the priority documents have been received in this national stage application from the		
International Bureau (PCT Rule 17.2(a)).		
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the requirements
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give		
5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.		
(a) 🔲 including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached		
1) 🗌 hereto or 2) 🔲 to Paper No./Mail Date		
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment or in the C	Office action of
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t	.84(c)) should be written on the drawing the header according to 37 CFR 1.121(ngs in the front (not the back) of d).
 DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL. 		
Attachment(s) 1. ☑ Notice of References Cited (PTO-892)	5. ☐ Notice of Informal P	atent Application (PTO-152)
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	6. Interview Summary	(PTO-413),
3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/0	Paper No./Mail Dat 08), 7. Examiner's Amendr	ne ment/Comment
Paper No./Mail Date <u>07 October 2005</u> 4. Examiner's Comment Regarding Requirement for Deposit	8. Examiner's Stateme	ent of Reasons for Allowance
of Biological Material	9.	6.
		Que T. Le Primary Examiner

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DETAILED ACTION

Allowable Subject Matter

1. Claims 1-29 are allowed.

2. The following is an examiner's statement of reasons for allowance:

The prior art fails to teach a near-field scanning optical microscope (NSOM), among other features, comprising an ultrafast laser source generating pulses of laser light with durations less than 1 ns and a peak wavelength; and a probe tip at one end of the NSOM probe with a cross-sectional area less than a square of the peak wavelength of the pulses of laser light.

The prior art further fails to teach a method for laser machining a feature on a microstructure workpiece, among other features, comprising the steps of: using the ultrafast laser source to generate pulses of laser light having pulses less than 1 ns and a peak wavelength.

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure:

I) Ghislain et al. (US 5,939,709) teach a scanning probe microscope using a high refractive index solid immersion lens (SIL) to provide optical images with a resolution better than the diffraction limit in air. The SIL has a spherical upper surface and a conical lower surface with a sharp tip. The focused spot size generates an evanescent wave having an amplitude that decays exponentially with distance from the SIL. A cantilever caries the SIL probe and a cantilever deflection sensor permits precise control of tip-sample forces and separation. The cantilever deflection sensor operates in a feedback loop to maintain the tip-sample gap within the near-field as the SIL probe scans over the sample to generate optical data.

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Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Pascal M. Bui-Pho whose telephone number is (571) 272-2714. The examiner can normally be reached on Monday through Friday: 8:30 a.m. - 5:00 p.m.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Georgia Epps can be reached on (571) 272-2328. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

pmb

Que T. Le Primary Examiner